

#### **A scalable model based RTL framework zamiaCAD for static analysis**

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#### **Application of high-level decision diagrams for simulation-based verification tasks**

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**Tihomirov, Valentin; Tšepurov, Anton; Saif Abrar, Syed; Jenihhin, Maksim; Raik, Jaan** DATE 2013 : Design Automation and Test in Europe, March 18-22, 2013, Grenoble, France 2013 / [1] p. : ill